

CMOS-6/6A/6V/6X 1.0-MICRON CMOS GATE ARRAYS

April 1992

Description

NEC's CMOS-6 gate array families (CMOS-6, CMOS-6A, CMOS-6V and CMOS-6X) are ultra-high performance, sub-micron effective channel length CMOS products created for high-integration ASIC applications.

The device processing includes 1.0-micron (drawn) silicon-gate CMOS technology and three-layer (CMOS-6) and two-layer (CMOS-6A, CMOS-6V, CMOS-6V) metallization. This technology features channelless (sea-of-gates) architecture in densities from 1,200 to 177,408 equivalent gates, with an internal gate delay of 270 ps (F/O=1; L = 0). Output drive is variable to 18 mA. Slew rate buffers are also available.

CMOS-6 products are fully supported by NEC's advanced ASIC design technology. NEC's OpenCAD® integration system lets the designer choose the most powerful design tools and services available. The CMOS-6/6A/6V macro cell (block) library is compatible with the powerful CMOS-5 block library, which contain over 300 cells and more than 100 interface options.

NEC offers advanced packaging solutions with both through-hole and surface-mount ceramic PGAs and flat packages. These heat-sink-equipped packages give CMOS-6 devices the performance edge in high-integration applications.

Features

- □ Channelless, 1.μm CMOS high-density architecture
- □ Variable output drive: 4.5, 9.0, 13.5, or 18.0 mA
- Slew rate output buffers
- = Free size memory blocks to 64 Kbytes (16K x 4, μPD65676)
- □ Powerful block library with more than 400 macros
- □ 3V characterized block library
- New 0.65 mm 184-pin plastic QFP for cost effective designs
- High I/O to gate ratio for CMOS-6V and CMOS-6X

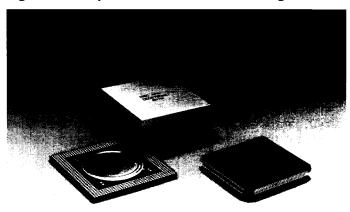
Publications

This data sheet contains preliminary specifications, package information, and operational data for the CMOS-6 gate array families. Additional design information is available in NEC's CMOS-6 Block Library and CMOS-6 Design Manual. Contact your local NEC Design Center or the NEC Literature Center for further ASIC design information; see the back of this data sheet for locations and phone numbers.

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70020-5

Figure 1. Sample CMOS-6/6A/6V/6X Packages



Gate Array Sizes

		Estimated	d Usable Gates	
Device	Available	•	Design =	I/O Pads
(μ PD)	Gates	50% Memory	All Random*	(Max.)
CMOS-6	X Devices			
65612	1,200	1,000	800	64
65622	2,700	2,300	1,900	84
65626	3,900	3,300	2,700	104
65632	5,600	3,900	3,900	104
CMOS-6	A Devices			
65630	5,376	4,600	3,800	84
65636	8,000	6,800	5,600	100
65640	11,520	9,800	8,100	120
65646	16,240	13,800	11,400	140
65650	21,120	18,000	14,800	160
65654	30,720	26,100	21,500	192
CMOS-6	V Devices			
65631	5,544	4,700	3,900	140
65641	11,520	9,800	8,100	160
65644	14,040	11,900	9,800	160
65647	16,240	13,800	11,400	160
65648	18,600	15,800	13,000	160
65651	21,120	18,000	14,800	220
65652	26,640	22,600	18,600	220
65655	30,720	26,100	21,500	, 220
CMOS-6	Devices			
65658	42,240	37,000	21,700	220
65664	72,576	63,500	54,400	288
65672	119,232	104,300	89,400	368
65676	177,408	155,200	133,100	448

Actual gate utilitization may vary depending on circuit implementation.

Utilization is 75% for three-layer metal; 70% for two-layer metal.

Memory utilization is determined by 50% x available gates + (utilization x 50% available gates)

Depending on package and circuit specification, some pads are used for ${\bf V}_{\rm DD}$ and GND and are unavailable as signal pads.



Circuit Architecture

CMOS-6 products are built with NEC's 1-micron channelless architecture. As shown in figure 2, CMOS gate array chips are divided into I/O and internal cell areas. The I/O cell area contains input and output buffers that isolate the internal cells from high-energy external signals. The internal cell area is an array of basic cells, each composed of two p-channel MOS transistors and two n-channel MOS transistors, as well as four additional n-channel MOS transistors for compact RAM design. A cell configured as a two-input NAND gate is shown in figure 3. These p-channel and n-channel transistors are sized to offer a superb ratio of speed to silicon area.

Figure 2. Chip Layout and Internal Cell Configuration

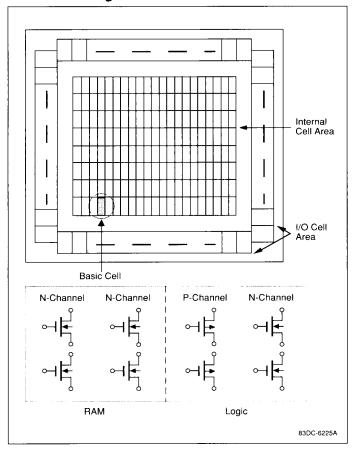
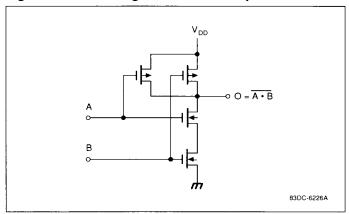


Figure 3. Cell Configured as a Two-Input NAND



Output Slew Rate Selection

Fast rise and fall times of CMOS output buffers can cause system noise and signal overshoot. When an unterminated line is being driven by a buffer, the maximum line length is determined by the rise and fall time of the output buffers and the round-trip signal delay of the line.

As a general rule, the round-trip delay of the line should not exceed the rise or fall time of the driving signal. Transmission lines that are longer than those determined by the above rule can cause system performance degradation because of reflections and ringing. One benefit of slew rate output buffers is that longer interconnections on a PC board (and routing flexibility) are possible with slew rate output buffers.

The ASIC designer can slow down the output edge rate by selecting the slew rate output buffer and thus allowing for a longer line.

Also, as the slew rate buffers inject less noise than their non-slew rate counterparts into the internal power and ground busses of the devices, the slew rate buffers require fewer power pairs for simultaneous switching outputs.



Absolute Maximum Ratings

Power supply voltage, V _{DD}	-0.5 to +6.5 V
Input/output voltage, V _I / V _O	-0.5 V to V _{DD} + 0.5 V
Latch-up current, I _{LATCH}	>1 A (typ)
Output current, I _O	
4.5-mA drive	10 mA
9-mA drive	20 mA
13.5-mA drive	30 mA
18-mA drive	40 mA
Operating temperature, T _{OPT}	−40 to +85°C
Storage temperature, T _{STG}	−65 to +150°C

Caution: Exposure to absolute maximum ratings for extended periods may affect device reliability; exceeding the ratings could cause permanent damage. The device should not be operated outside the recommended operating conditions.

Input/Output Capacitance

 $V_{DD} = V_{I} = 0 \text{ V; } f = 1 \text{ MHz}$

Terminal	Symbol	Тур	Max	Unit
Input	C _{IN}	10	25	pF
Output	C _{OUT}	10	25	pF
I/O	C _{I/O}	10	25	pF

Note:

(1) Values include package pin capacitance.

Power Consumption

Description	Limits (max)	Unit	Test Conditions
Internal cell	8	μ W / M Hz	F/O = 3; L = 3 mm
Input block	46	μW/MHz	F/O = 3; L = 3 mm
Output block	.98	mW/MHz	C ₁ = 15 pF

Recommended Operating Conditions

		смоя	Level	ΠL	-	
Parameter	Symbol	Min	Max	Min	Max	Unit
Power supply voltage	V _{DD}	4.5	5.5	4.75	5.25	V
Ambient temperature	T _A	-40	+85	0	+70	°C
Low-level input voltage	V _{IL}	0	0.3 V _{DD}	0	0.8	V
High-level input voltage	V _{IH}	0.7 V _{DD}	V _{DD}	2.2	V _{DD}	V
Input rise or fall time	t _R , t _F	0	200	0	200	ns
Input rise or fall time, Schmitt	t _R , t _F	0	10	0	10	ms
Positive Schmitt-trigger voltage	V _P	1.8	4.0	1.2	2.4	V
Negative Schmitt-trigger voltage	V _N	0.6	3.1	0.6	1.8	V
Hysteresis voltage	V _H	0.3	1.5	0.3	1.5	V

AC Characteristics

 $V_{DD} = 5 \text{ V} \pm 10\%; \ T_{A} = -40 \text{ to } +85^{\circ}\text{C}$

Parameter	Symbol	Min	Тур	Max	Unit	Conditions
Toggle frequency	f _{TOG}	120			MHz	D-F/F; F/O = 2
Delay time, internal gate	t _{PD}		270		ps	F/O = 1; L = 0 mm
Delay time, 2-input NAND gate			700		ps	F/O = 3; L = 3 mm
Delay time, buffer						
Input (FI01)	t _{PD}		1.25		ns	F/O = 3; L = 3 mm
Output (FO01)	t _{PD}		2.0		ns	C _L = 15 pF
Output rise time	t _B		3.0		ns	C _L = 15 pF
Output fall time	t _F	******	2.0	-	ns	C _L = 15 pF



DC Characteristics

 $V_{DD} = 5~V \pm 10\%$; $T_A = -40~to~+85~^{\circ}C$

Parameter	Symbol	Min	Тур	Max	Unit	Conditions
Quiescent current (Note 1)	IL		0.1	400	μА	$V_1 = V_{DD}$ or GND
Input leakage current		•			•	
Regular	I ₁		10 ⁻⁵	10	μΑ	$V_{l} = V_{DD}$ or GND
50 kΩ pull-up	I _I	-40	-100	-270	μΑ	V _I = GND
5 kΩ pull-up	I ₁	-0.35	-1.0	-2.2	mA	V _I = GND
50 kΩ pull-down	l ₁	45	120	300	μΑ	$V_I = V_{DD}$
Off-state output leakage current	l _{oz}			10	μA	$V_O = V_{DD}$ or GND
Input clamp voltage	V _{IC}	-1.2			V	I _I = 18 mA
Output short circuit current (Note 2)	los	-250			mA	V _O = 0 V
Low-level output current (CMOS)						
4.5 mA (Note 3)	l _{oL}	4.5			mA	V _{OL} = 0.4 V
9 mA (Note 3)	l _{OL}	9.0			mA	V _{OL} = 0.4 V
13.5 mA (Note 3)	l _{oL}	13.5			mA	V _{OL} = 0.4 V
18 mA (Note 3)	l _{oL}	18.0			mA	V _{OL} = 0.4 V
High-level output current (CMOS)			-			
4.5 mA (Note 3)	I _{OH}	-2.5			mA	$V_{OH} = V_{DD} - 0.4 V$
9 mA (Note 3)	I _{OH}	-5.0			mA	$V_{OH} = V_{DD} - 0.4 V$
13.5 mA (Note 3)	I _{OH}	-7.5			mA	$V_{OH} = V_{DD} - 0.4 V$
18 mA (Note 3)	I _{OH}	-10.0			mA	$V_{OH} = V_{DD} - 0.4 V$
Low-level output current (TTL)						
9 mA (Note 4)	I _{OL}	9.0			mA	V _{OL} = 0.4 V
18 mA (Note 4)	I _{OL}	18.0			mA	V _{OL} = 0.4 V
High-level output current (TTL)						
9 mA (Note 4)	I _{OH}	-0.5			mA	V _{OH} = 2.4 V
18 mA (Note 4)	Гон	-1.0			mA	V _{OH} = 2.4 V
Low-level output voltage	V _{OL}			0.1	V	I _{OL} = 0 mA
High-level output voltage (CMOS) (Note 3)	V _{OH}	V _{DD} -0.1			V	I _{OH} = 0 mA
High-level output voltage (TTL) (Note 4)	V _{OH}	2.6	3.4		٧	I _{OH} = 0 mA

Notes:

⁽¹⁾ The maximum value reflects the use of pull-up/pull-down resistors and oscillator blocks. Contact an NEC ASIC Design Center for assistance in calculation.

⁽²⁾ Rating is for only one output operating in this mode for less than 1 second.

 $[\]begin{array}{ll} \text{(3)} & \text{CMOS-level output buffer (V}_{\text{DD}} = 5 \text{ V} \pm 10\%, \text{ T}_{\text{A}} = -40 \text{ to } +85^{\circ}\text{C}). \\ \text{(4)} & \text{TTL-level output buffer (V}_{\text{DD}} = 5 \text{ V} \pm 5\%, \text{ T}_{\text{A}} = 0 \text{ to } +70^{\circ}\text{C}). \\ \end{array}$



Package Plan

100-pin	CMOS-6 μ PD 65xxx
Maximum I/O Pins 64 84 104 104 84 100 120 140 160 192 140 160 160 160 160 220 220 22 Plastic Quad Flatpack (QFP) 44-pin	5 658 664 672 670
Plastic Quad Flatpack (QFP) 44-pin	.5 21.7 54.4 89.4 13
44-pin	0 220 288 368 44
52-pin	
120-pin 136-pin 136-pin 160-pin 184-pin 184-pin 180-pin 180-pin 180-pin 180-pin 180-pin 180-pin 180-pin 190-pin 190-pi	
Thin Quad Flatpack (TQFP) 80-pin	A A A A A A A A
80-pin A Shrink Plastic Quad Flatpack (QFP-FP) (.5 mm Lead Pitch) 100-pin	A A A A
Shrink Plastic Quad Flatpack (QFP-FP) (.5 mm Lead Pitch)	
100-pin	
208-pin* 304-pin Ceramic Pin Grid Array (PGA) 72-pin AAAA 132-pin AAAAA 176-pin AAAAA 208-pin 280-pin	A A A A A A A A
72-pin A A A A A A A A A A A A A A A A A A A	A A A A A A A A E E E
132-pin A A A A A A A A A A A A A A A A A A A	
·	A A A A A A A A A A A A
364-pin	A A A A A
Ceramic Pin Grid Array (PGA) (Butt Lead)	
288-pin 528-pin (with heat sink) 528-pin (without heat sink)	A ¹ A A A
Plastic Leaded Chip Carrier (PLCC)	
68-pin 84-pin	A A

A = Available

NOTE: NEC reserves the right to alter the package plan based on the results of qualification. For current package availability, please contact your local NEC Design Center.

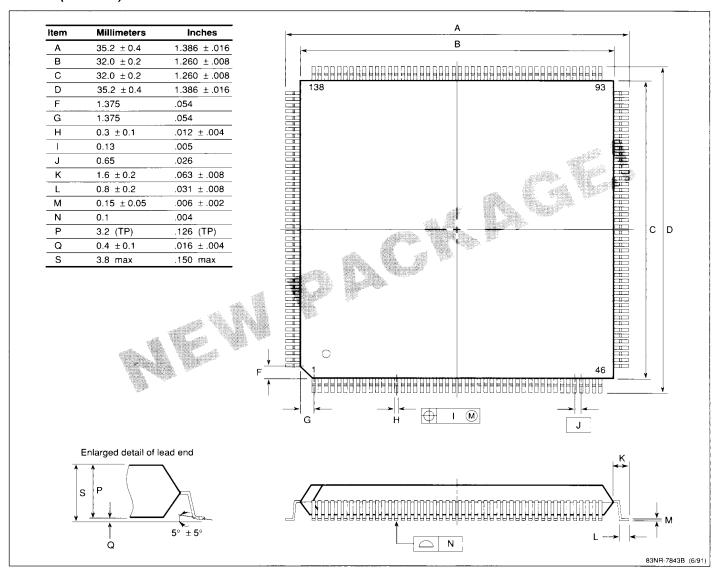
A1= Need advanced notice

E = Under Evaluation

^{* =} Heat spreader under evaluation

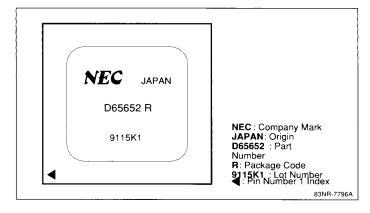


184-Pin (0.65 mm) Plastic QFP



The new 184-pin 0.65 mm QFP shown above is ideal for PC integrated chipsets. The package is available with a copper leadframe thereby allowing greater heat dissipation than standard 42 alloy leadframe packages. The 0.65 mm pin pitch allows the use of widely available, cost effective assembly equipment. It is currently available in two masterslices. The $\mu PD65658$ with 25,344 usable gates and the $\mu PD65664$ with 43,545 usable gates.

Typical Package Marking





NEC's ASIC Design System

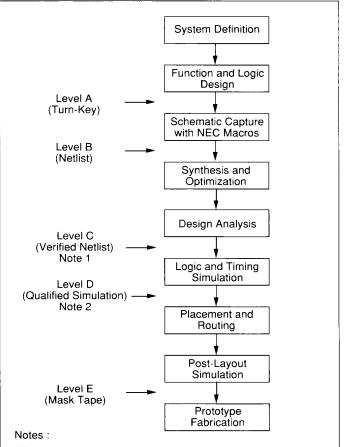
CMOS-6/6A/6V gate arrays are fully supported by NEC's network of ASIC Design Centers, listed on the back of this data sheet.

Design flow for CMOS-6/6A/6V gate arrays is shown in figure 4. Users can enlist Design Center support at any step in the design flow before actual manufacturing. Figure 4 shows the various levels at which Design Center support may begin — anywhere from level A through level E. Level C, "Verified Netlist," is the most popular interface.

NEC supports its ASIC products with a comprehensive CAD system that significantly reduces the time and expense usually associated with the development of semicustom devices. NEC's OpenCAD integration system supports tools for floorplanning, logic synthesis, automatic test generation, accelerated fault grading and full timing simulation, and advanced place-and-route algorithms. These advanced CAD tools ensure accurate designs.

Sample design kits are available at no charge to qualified users: contact an NEC ASIC Design Center for more information. (Software licensing required—NEC reserves the right to prioritize support based on user requirements.)

Figure 4. Gate Array Design Flow



- (1) NEC supports the most popular workstations, including Mentor Graphics, Valid, DAZIX®, FutureNet, Viewlogic®, and HP9000 workstations, for the NEC ASIC product line. However, NEC does not support all workstations for all products. Please contact your nearest NEC ASIC Design Center for more information.
- (2) NEC provides support of System HILO®, Verilog®, and MACH 1000/1500™ interface capability.

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Description

I_{OL} Cells

18.0 1 (6)

18.0 1 (6)

9.0

1 (8)

Block Library List

The CMOS-6 families offer a variety of blocks, including gates, flip-flop circuits, and shift registers. The functions of these blocks are designed to be compatible with those of the CMOS-4 and CMOS-5 families.

low-pe partic consid standa and h	dition, such memory blocks as RAM and ower gates are provided. The low-power ular, was designed with low fan-out to deration; the number of cells is less than to ard block, contributing to low power corigh efficiency. k List	blo aker hat	ck, in into of the	BOUE BOUE BOWE BTO8 BTU8 BTW8	5 kΩ pull-up res. Output buffer, CMOS 3-state out Output buffer, CMOS 3-state out, 50 kΩ pull-down res. Output buffer, CMOS 3-state out, 50 kΩ pull-up re Output buffer, CMOS 3-state out, 50 kΩ pull-up res Output buffer, TTL 3-state out, 50 kΩ pull-up res. Output buffer, TTL 3-state out, 50 kΩ pull-up res. Output buffer, TTL 3-state out, 50 kΩ pull-up res.		1 (5) 1 (5) 1 (5) 1 (5) 1 (6) 1 (6) 1 (6)
Block Name	Description	I _{OL} (mA)	Cells	BT09 BTU9 BTW9	Output buffer, TTL 3-state out Output buffer, TTL 3-state out, 50 k Ω pull-up res. Output buffer, TTL 3-state out, 50 k Ω pull-up res.	18.0 18.0	2 (12) 2 (12) 2 (12)
l4-	Interface Blocks			EXT1 EXT3	Output buffer, N-ch open drain Output buffer, N-ch open drain, 50 k Ω pull-up res.	9.0 9.0	1 (2) 1 (2)
Inputs FI01	Input buffer, CMOS in	_	1 (3)	EXW3 EXT2	Output buffer, N-ch open drain, 5 k Ω pull-up res. Output buffer, P-ch open drain	9.0 *9.0	1 (2) 1 (2)
FID1 FIU1 FIW1	Input buffer, CMOS in, 50 k Ω pull-down res. Input buffer, CMOS in, 50 k Ω pull-up res. Input buffer, CMOS in, 5 k Ω pull-up res.	- - -	1 (3) 1 (3) 1 (3)	EXT4 EXT5 EXT7 EXW7	Output buffer, P-ch open drain, 50 k Ω pull-up res. Output buffer, N-ch open drain Output buffer, N-ch open drain, 50 k Ω pull-up res.	*9.0 18.0	1 (2) 1 (2) 1 (2)
FI02 FID2 FIU2 FIW2	Input buffer, TTL in Input buffer, TTL in, 50 k Ω pull-down res. Input buffer, TTL in, 50 k Ω pull-up res. Input buffer, TTL in, 5 k Ω pull-up res.	-	1 (3) 1 (3) 1 (3) 1 (3)	EXT6 EXT8	Output buffer, N-ch open drain, $5 \text{ k}\Omega$ pull-up res. Output buffer, P-ch open drain, $50 \text{ k}\Omega$ pull-up res. Output buffer, P-ch open drain, $50 \text{ k}\Omega$ pull-down res.		1 (2) 1 (2) 1 (2)
FIB1 FIB2 FDS1	Input buffer, CMOS in, high fanout for clock driver Input buffer, TTL in, high fanout for clock driver Input buffer, CMOS Schmitt in, 50 k Ω pull-down restricted to the first content of the content o		1 (24) 1 (24) 1 (6)	EXT9 EXTB EXWB	Output buffer, N-ch open drain Output buffer, N-ch open drain, $50 \text{ k}\Omega$ pull-up res. Output buffer, N-ch open drain, $5 \text{ k}\Omega$ pull-up res.		1 (2) 1 (2) 1 (2)
FIS1 FUS1	Input buffer, CMOS Schmitt in Input buffer, CMOS Schmitt in, 50 k Ω pull-up res.	-	1 (6) 1 (6)	* Indic	cates I _{OH}		
FWS1	Input buffer, CMOS Schmitt in, 5 k Ω pull-up res.	-	1 (6)	I/O But	ifers		
FDS2 FIS2	Input buffer, TTL Schmitt in, 50 k Ω pull-down res. Input buffer, TTL Schmitt in	-	1 (6) 1 (6)	B001 B0D1	I/O buffer, CMOS in, CMOS 3-state out I/O buffer, CMOS in, CMOS 3-state out,	13.5 13.5	1 (9) 1 (9)
FUS2 FWS2	Input buffer, TTL Schmitt in, $50 \text{ k}\Omega$ pull-up res. Input buffer, TTL Schmitt in, $5 \text{ k}\Omega$ pull-up res.	-	1 (6) 1 (6)	B0U1	50 k Ω pull-down res. I/O buffer, CMOS in, CMOS 3-state out,	13.5	1 (9)
Output	ts			B0W1	50 kΩ pull-up res. I/O buffer, CMOS in, CMOS 3-state out,	13.5	1 (9)
FO01 FO02	Output buffer, CMOS out Output buffer, CMOS out	9.0 13.5	1 (2) 1 (4)		5 k Ω pull-up res.		
FO03 FO04		18.0 4.5	1 (4) 1 (2)	B002 B0D2	I/O buffer, TTL in, CMOS 3-state out I/O buffer, TTL in, CMOS 3-state out, 50 k Ω pull-down res.	13.5 13.5	1 (9) 1 (9)
FT01	Output buffer, TTL out	9.0	1 (4)	B0U2	I/O buffer, TTL in, CMOS 3-state out,	13.5	1 (9)
FT02 B007 B0D7	Output buffer, CMOS 3-state out Output buffer, CMOS 3-state out,	18.0 13.5 13.5	2 (6) 1 (6) 1 (6)	B0W2	50 k Ω pull-up res. I/O buffer, TTL in, CMOS 3-state out, 5 k Ω pull-up res.	13.5	1 (9)
B0U7	•	13.5	1 (6)	B003 B0D3	I/O buffer, CMOS in, CMOS 3-state out I/O buffer, CMOS in, CMOS 3-state out,	9.0 9.0	1 (8) 1 (8)
B0W7	50 kΩ pull-up res. Output buffer, CMOS 3-state out, 5 kΩ pull-up res.		1 (6)	B0U3	50 k Ω pull-down res. I/O buffer, CMOS in, CMOS 3-state out,	9.0	1 (8)
B008 B0D8	Output buffer, CMOS 3-state out Output buffer, CMOS 3-state out, $50 \text{ k}\Omega$ pull-down res.	9.0 9.0	1 (5) 1 (5)	B0W3	50 k Ω pull-up res. I/O buffer, CMOS in, CMOS 3-state out, 5 k Ω pull-up res.	9.0	1 (8)
B0U8 B0W8	Output buffer, CMOS 3-state out, 50 k Ω pull-up resolutput buffer, CMOS 3-state out, 5 k Ω pull-up resolution.	9.0	1 (5) 1 (5)	B004 B0D4	I/O buffer, TTL in, CMOS 3-state out I/O buffer, TTL in, CMOS 3-state out,	9.0 9.0	1 (8) 1 (8)
B009 B0D9		18.0 18.0	1 (6) 1 (6)	B0U4	50 kΩ pull-down res. I/O buffer, TTL in, CMOS 3-state out,	9.0	1 (8)

Block

Name

Outputs (Cont.)

B0U9 Output buffer, CMOS 3-state out,

50 k Ω pull-up res. B0W9 Output buffer, CMOS 3-state out,

 $5 \text{ k}\Omega$ pull-up res.

50 k Ω pull-up res.

B0W4 I/O buffer, TTL in, CMOS out, 5 k Ω pull-up res.

Note: Number of internal cells required is shown in parentheses.

8

50 k Ω pull-down res.



Block Name	Description	l _{OL} (mA)	Cells	Block Name	Description	I _{OL} (mA)	Cells
	Interface Blocks (Cont.)				Interface Blocks (Cont.)		
I/O Buf	fers (Cont.)			I/O Buf	fers (Cont.)		
B005	I/O buffer, CMOS in, CMOS 3-state out	18.0	1 (9)	BSD4	I/O buffer, TTL Schmitt in, CMOS 3-state out,	9.0	1 (11)
B0D5	I/O buffer, CMOS in, CMOS 3-state out,	18.0	1 (9)	DO14	50 kΩ pull-down res.	0.0	4 (44)
DOLIE	50 k Ω pull-down res. I/O buffer, CMOS in, CMOS 3-state out,	18.0	1 (9)	BSI4 BSU4	I/O buffer, TTL Schmitt in, CMOS 3-state out I/O buffer, TTL Schmitt in, CMOS 3-state out,		1 (11)
B0U5	50 k Ω pull-up res.	10.0	1 (3)		50 k Ω pull-up res.		, ,
B0W5	l/O buffer, CMOS in, CMOS 3-state out, 5 kΩ pull-up res.	18.0	1 (9)	BSW4	I/O buffer, TTL Schmitt in, CMOS 3-state out, 5 k Ω pull-up res.	9.0	1 (11)
B006	I/O buffer, TTL in, CMOS 3-state out	18.0	1 (9)	BSD5	I/O buffer, CMOS Schmitt in, CMOS 3-state out,	18.0	1 (12)
B0D6	I/O buffer, TTL in, CMOS 3-state out,	18.0	1 (9)	BSI5	50 k Ω pull-down res. I/O buffer, CMOS Schmitt in, CMOS 3-state out	18.0	1 (12)
B0U6	50 k Ω pull-down res. I/O buffer, TTL in, CMOS 3-state out,	18.0	1 (9)	BSU5	I/O buffer, CMOS Schmitt in, CMOS 3-state out,		1 (12)
БООО	50 kΩ pull-up res.	10.0	. (0)		50 kΩ pull-up res.	40.0	4 (40)
B0W6	I/O buffer, TTL in, CMOS 3-state out, 5 $k\Omega$ pull-up res.	18.0	1 (9)	BSW5	I/O buffer, CMOS Schmitt in, CMOS 3-state out, 5 k Ω pull-up res.	18.0	1 (12)
B00A	I/O buffer, TTL in, TTL 3-state out	9.0	1 (9)	BSD6	I/O buffer, TTL Schmitt in, CMOS 3-state out,	18.0	1 (12)
B0UA	I/O buffer, TTL in, TTL 3-state out,	9.0	1 (9)	BSI6	50 k Ω pull-down res. I/O buffer, TTL Schmitt in, CMOS 3-state out	18.0	1 (12)
B0WA	50 kΩ pull-up res. I/O buffer, TTL in, TTL 3-state out, 5 kΩ pull-up re	es. 9.0	1 (9)	BSU6	I/O buffer, TTL Schmitt in, CMOS 3-state out,		1 (12)
B00B	I/O buffer, TTL in, TTL 3-state out		2 (15)	DOMO	50 kΩ pull-up res.	10.0	1 (10)
B0UB	I/O buffer, TTL in, TTL 3-state out, 50 k Ω pull-up res.	18.0	2 (15)	BSW6	I/O buffer, TTL Schmitt in, CMOS 3-state out, 5 k Ω pull-up res.	10.0	1 (12)
B0WB	I/O buffer, TTL in, TTL 3-state out, 5 k Ω pull-up re	es.18.0	2 (15)	BSIA	I/O buffer, TTL Schmitt in, TTL 3-state out		1 (12)
B00C	I/O buffer, CMOS in, CMOS 3-state out	4.5	1(8)	BSUA	I/O buffer, TTL Schmitt in, TTL 3-state out, 50 k Ω pull-up res.	9.0	1 (12)
B0DC	I/O buffer, CMOS in, CMOS 3-state out, 50 k Ω pull-down res.	4.5	1(8)	BSWA	I/O buffer, TTL Schmitt in, TTL 3-state out, $6 \mathrm{k}\Omega$ pull-up res.	9.0	1 (12)
B0UC	I/O buffer, CMOS in, CMOS 3-state out,	4.5	1 (8)	BSIB	I/O buffer, TTL Schmitt in, TTL 3-state out	18.0	2 (18)
B0WC	50 k Ω pull-up res. I/O buffer, CMOS in, CMOS 3-state out, 5 k Ω pull-up res.	4.5	1 (8)	BSUB	I/O buffer, TTL Schmitt in, TTL 3-state out, 50 k Ω pull-up res.	18.0	2 (18)
B00D	I/O buffer, TTL in, CMOS 3-state out I/O buffer, TTL in, CMOS 3-state out,	4.5 4.5	1 (8) 1 (8)	BSWB	I/O buffer, TTL Schmitt in, TTL 3-state out, $6 k\Omega$ pull-up res.	18.0	2 (18)
DODD	50 k Ω pull-down res.		. (0)	BSDC	I/O buffer, CMOS Schmitt in, CMOS 3-state out,	4.5	1 (11)
B0UD	I/O buffer, TTL in, CMOS 3-state out,	4.5	1 (8)	D010	50 kΩ pull-down res.	4 5	4 /44\
DOMD	50 kΩ pull-up res. I/O buffer, TTL in, CMOS 3-state out,	4.5	1 (8)	BSIC	I/O buffer, CMOS Schmitt in, CMOS 3-state out		1 (11)
BUVVD	5 k $Ω$ pull-up res.	4.5	1 (0)	BSUC	I/O buffer, CMOS Schmitt in, CMOS 3-state out, 50 k Ω pull-up res.	4.5	1 (11)
BSD1	I/O buffer, CMOS Schmitt in, CMOS 3-state out, 50 k Ω pull-down res.		1 (12)	BSWC	I/O buffer, CMOS Schmitt in, CMOS 3-state out, 5 k Ω pull-up res.	4.5	1 (11)
BSI1	I/O buffer, CMOS Schmitt in, CMOS 3-state out		1 (12)	BSDD	I/O buffer, TTL Schmitt in, CMOS 3-state out,	4.5	1 (11)
BSU1	I/O buffer, CMOS Schmitt in, CMOS 3-state out, 50 k Ω pull-up res.	13.5	1 (12)	DOID	50 kΩ pull-down res.	4 5	4 (44)
BSW1	I/O buffer, CMOS Schmitt in, CMOS 3-state out,	13.5	1 (12)	BSID	I/O buffer, TTL Schmitt in, CMOS 3-state out		1 (11)
BSD2	5 k Ω pull-up res. I/O buffer, TTL Schmitt in, CMOS 3-state out,	13.5	1 (12)	BSUD	I/O buffer, TTL Schmitt in, CMOS 3-state out, 50 k Ω pull-up res. I/O buffer, TTL Schmitt in, CMOS 3-state out,		1 (11)
BSI2	50 k Ω pull-down res. I/O buffer, TTL Schmitt in, CMOS 3-state out	13.5	1 (12)	63446	5 kΩ pull-up res.	4.5	. ()
	I/O buffer, TTL Schmitt in, CMOS 3-state out,	13.5	1 (12)	Slew F	Rate Output Buffers		
BSW2	50 k Ω pull-up res. I/O buffer, TTL Schmitt in, CMOS 3-state out,	13.5	1 (12)	FE03 BE09	18 mA CMOS level slew rate output buffer 18 mA CMOS 3-state slew rate output buffer		1 (4) 1 (5)
BSD3	5 kΩ pull-up res. I/O buffer, CMOS Schmitt in, CMOS 3-state out, 50 kΩ pull-down res.	9.0	1 (11)	BED9	18 mA CMOS 3-state slew rate output buffer with 50K pull-down res.		1 (5)
BSI3	I/O buffer, CMOS Schmitt in, CMOS 3-state out	9.0	1 (11)	BEU9	18 mA CMOS 3-state slew rate output buffer with 50K pull-up res.		1 (5)
BSU3	I/O buffer, CMOS Schmitt in, CMOS 3-state out,	9.0	1 (11)	BEMO			
BSW3	50 k Ω pull-up res. I/O buffer, CMOS Schmitt in, CMOS 3-state out,	9.0	1 (11)	BE05	18 mA CMOS 3-state slew rate output buffer with 5K pull-up res.18 mA I/O slew rate buffer (CMOS in / CMOS out)		1 (5) 1 (8)
Note:	$5~\text{k}\Omega$ pull-up res. Number of internal cells required is shown in parel	ntheses	i.	BED5	18 mA I/O slew rate buffer (CMOS in / CMOS out) with 50K pull-down res.		1 (8)
	·				•		c



Block Name	Description	Cells	Block Name	Description	Cells
	Interface Blocks (Cont.)			Function Blocks - Normal Power	
Slew R	ate Output Buffers (Cont.)		Inverte		
BEU5	18 mA I/O slew rate buffer (CMOS in / CMOS out) with 50K pull-up res.	1 (8)	F101 F102 F103	Inverter $(F/O = 17)$ Inverter $(F/O = 37)$ Inverter $(F/O = 60)$	1 2
BEW5	18 mA I/O slew rate buffer (CMOS in / CMOS out) with 5K pull-up res.	1 (8)	F104	Inverter $(F/O = 92)$	3
BE06 BED6	18 mA I/O slew rate buffer (TTL in / CMOS out) 18 mA I/O slew rate buffer (TTL in / CMOS out) with 50K pull-down res.	1 (8) 1 (8)	F108 Buffer	Inverter (F/O = 160) s	12
BEU6	18 mA I/O slew rate buffer (TTL in / CMOS out) with 50K pull-up res.	1 (8)	F111 F112	Non-inverting buffer (F/O = 17) Non-inverting buffer (F/O = 35)	2 3
BEW6	18 mA I/O slew rate buffer (TTL in / CMOS out)	1 (8)	F113	Non-inverting buffer $(F/O = 54)$	4
BFI5	with 5K pull-up res. 18 mA Schmitt I/O slew rate buffer (CMOS in / CMOS out)	1 (11)	F114 F118	Non-inverting buffer ($F/O = 74$) Non-inverting buffer ($F/O = 180$)	5 11
BFD5	18 mA Schmitt I/O slew rate buffer (CMOS in / CMOS out) with 50K pull-down res.	1 (11)	NOR C	Gates	
BFU5	18 mA Schmitt I/O slew rate buffer	1 (11)	F202 F203	2-input NOR 3-input NOR	2
BFW5	(CMOS in / CMOS out) with 50K pull-up res. 18 mA Schmitt I/O slew rate buffer	1 (11)	F204 F208	4-input NOR 8-input NOR	4 7
BFI6	(CMOS in / CMOS out) with 5K pull-up res. 18 mA Schmitt I/O slew rate buffer (TTL in / CMOS out)	1 (11)	F222 F223	2-input NOR, power 3-input NOR, power	4 6
BFD6	18 mA Schmitt I/O slew rate buffer (TTL in / CMOS out) with 50K pull-down res.	1 (11)	F224	4-input NOR, power	8
BFU6	18 mA Schmitt I/O slew rate buffer	1 (11)	OR Ga F212	2-input OR	2
BFW6	(TTL in / CMOS out) with 50K pull-up res. 18 mA Schmitt I/O slew rate buffer (TTL in / CMOS out) with 5K pull-up res.	1 (11)	F213 F214	3-input OR 4-input OR	3
	, , ,		F232 F233	2-input OR, power 3-input OR, power	3
Specia FIB1	Il Blocks Input buffer, CMOS in, high fanout for clock driver	1 (24)	F234	4-input OR, power	4
FIB2 OSF1	Input buffer, TTL in, high fanout for clock driver	1 (24)	NAND	Gates	
OSF2	Feedback resistance for oscillator (low freq.) Feedback resistance for oscillator (high freq.)	1	F302	2-input NAND	2
OSF3	Feedback resistance for oscillator with Enable (low freq.)	1	F303 F304	3-input NAND 4-input NAND	3 4
OSF4	Feedback resistance for oscillator with Enable (high freq.)	1	F305 F306	5-input NAND 6-input NAND	5 5
OSI1	Oscillator input buffer	1	F308	8-input NAND	6
OSI2 OSO1	Oscillator input buffer with Enable	1	F322	2-input NAND, power	4
OSO2		1	F323 F324	3-input NAND, power 4-input NAND, power	6 8
OSO3 OSO4	. , , , ,	1	AND G	Gates	
OSO7	Oscillator output buffer with feedback res. & Enable	1	F312	2-input AND	2
OSO8	•	1	F313 F314	3-input AND 4-input AND	3
SHT1	(high freq.) Monostable multivibrator	1	F332 F333 F334	2-input AND, power 3-input AND, power 4-input AND, power	3 4 4
	Oscillator pins must be used in combination. Some valuations are:	id		NOR Gates	4
	SI1 + OSO1 Low Frequency		F421	2-wide 1-2-input AND-OR inverter	3
0	SI1 + OSO3 + OSF1 Low Frequency SI1 + OSO2 High Frequency	-hl-	F422 F423	3-wide 1-1-2-input AND-OR inverter 2-wide 1-3-input AND-OR inverter	4 4
	SI2 + OSO7 Low Frequency with oscillator En SI2 + OSO3 + OSF3 Low Frequency with oscillator En		F424 F425	2-wide 2-2-input AND-OR inverter 3-wide 2-2-2-input AND-OR inverter	4
0	SI2 + OSO8 High Frequency with oscillator Er SI2 + OSO4 + OSF4 High Frequency with oscillator En	nable	F426 F429	2-wide 2-2-2-input AND-OR inverter 4-wide 2-2-2-2-input AND-OR inverter	6 8
10					



Block Name	Description	Cells	Block Name	Description (Cells
	Function Blocks - Normal Power (Cont.)			Function Blocks - Normal Power (Cont.)	
OR-NA	ND Gates		Flip-Fle	ops	
F431 F432 F433	2-wide 1-2-input OR-AND inverter 3-wide 1-1-2-input OR-AND inverter 2-wide 1-3-input OR-AND inverter	3 4 4	F596 F611 F614	Synchronous R-S F/F with Set-Reset D-F/F D-F/F with Set-Reset	11 8 10
F434	2-wide 2-2-input OR-AND inverter	4	F617	D-F/F with Set-Reset low	10
F435 F436 F454	2-wide 2-3-input OR-AND inverter 2-wide 3-3-input OR-AND inverter 4-wide 2-2-2-input OR-AND inverter	5 6 8	F631 F637 F641 F647	D-F/F C low D-F/F C low with Set-Reset low D-F/F, buffered D-F/F with Set-Reset low, buffered	8 10 8 10
Clock	Drivers		F661	D-F/F C low, buffered	8
F501 F502 FCK1 FCK2	Clock driver Dual clock driver Clock driver (F/O = 360) Clock driver (F/O = 720)	0 0 40 80	F667 F714 F717 F737	D-F/F C low with Set-Reset low, buffered Toggle F/F with Set-Reset Toggle F/F with Set-Reset low Toggle low F/F with Set-Reset low	10 9 9
FCK3 FCK4 FCK5	Clock driver (F/O = 1080) Clock driver (F/O = 1440)	120 160 200	F744 F747 F767	Toggle F/F with Set-Reset, buffered Toggle F/F with Set-Reset low, buffered Toggle low F/F with Set-Reset low, buffered	9
EV 05	l Coto		F771 F774	J-K F/F, buffered J-K F/F with Set-Reset, buffered	10 12
EX-OF F511	Exclusive-OR	4	F774 F777 F781	J-K F/F with Set-Reset low, buffered J-K F/F C low, buffered	12
EX-NC F512 Adder		4	F787 F791 F792 F922	J-K F/F C low with Set-Reset low, buffered Toggle F/F with Set-Reset and Tog. Enable Toggle low F/F with Set-Reset and Tog. Enable low 4-bit D-F/F with Reset	12 12 12 33
		9	F924	4-bit D-F/F	28
F521 F523	1-bit full-adder 4-bit binary full-adder	32	Counte	ore.	
Buffer		_	F961 F962	4-bit synchronous binary counter with Reset low, buffered 4-bit synchronous binary up counter with Reset low	52 38
F531 F532	3-state buffer with Enable 3-state buffer with Enable low	5 5	Compa	arator	
Decod	lers		F985	4-bit magnitude comparator	32
F561	2-to-4 decoder	10	Scan		
F981 F982 Shift F	2-to-4 decoder with Enable low 3-to-8 decoder with Enable low Registers	13 26	S000 S002 S050 S052	Scan path D-F/F with Set-Reset Scan path D-F/F Scan path D-F/F with Set-Reset, Hold Scan path D-F/F with Hold	11 9 14 12
F911	4-bit shift register with Reset	33	S100	Scan path J-K F/F with Set-Reset	14
F912 F913 F914	4-bit serial/parallel shift register 4-bit parallel shift register with Reset low, Load 4-bit shift register	35 39 28	\$102 \$150 \$152	Scan path J-K F/F Scan path J-K F/F with Set-Reset, Hold Scan path J-K F/F with Hold	12 17 15
Multip	lexers		S201	Scan path D-latch with Reset	12
F569 F570 F571	8-to-1 multiplexer 4-to-1 multiplexer 2-to-1 multiplexer	18 10 6	S202 S301 S302	Scan path D-latch Scan path D-latch with Reset (ATG) Scan path D-latch (ATG)	11 8 7
F572	Quad 2-to-1 multiplexer	14	S999	Scan path 2-to-1 data selector	2
Latch	es		Dalassa		
F595 F601 F602	R-S latch D-latch D-latch with Reset	5 6 6	F130 F131	Delay block (for monostable multivibrator) Delay gate	8
F603 F604	D-latch with Reset low D-latch with G driver low	7 6	F132	Delay gate	1
F605	D-latch with G low, Reset low	7			
F901	4-bit D-latch	20			
F902	8-bit D-latch	38			



Block Name	Description	Cells	Block Name	Description	Cells
	Function Blocks - Low Power			Function Blocks - Low Power	
Multip	lexer		OP-N/	AND Gates	
L572	Quad 2-to-1 multiplexer	10	• • • • • • • • • • • • • • • • • • • •		•
	·		L431 L432	2-wide 1-2-input OR-AND inverter 3-wide 1-1-2-input OR-AND inverter	2 2
Latche	es		L432	2-wide 1-3-input OR-AND inverter	2
L601	D-latch	3	L434	2-wide 2-2-input OR-AND inverter	2
L602	D-latch with Reset	4		_	_
L603	D-latch with Reset low	4	1.405	O saids O O issued OD AND issued	
L604	D-latch with G low driver	3	L435 L436	2-wide 2-3-input OR-AND inverter 2-wide 3-3-input OR-AND inverter	3
L605	D-latch with G low, R low	4	L456 L454	4-wide 2-2-2-input OR-AND inverter	3 4
L901	4-bit latch	10	L434	4-wide 2-2-2-input On-AND inverter	4
L902	8-bit latch	18	EX-OF	Gate	
			L511	EX-OR	3
Inverte			2011		9
L101	Inverter	1	EX-NC	PR Gate	
Buffer			L512	EX-NOR	3
L111	Non-inverting buffer	1	Decod	ers	
NOR C	Pates		L561	2-to-4 decoder	6
			L981	2-to-4 decoder with Enable low	8
L202	2-input NOR	1	L982	3-to-8 decoder with Enable low	17
L203 L204	3-input NOR 4-input NOR	2 2			
L204	+ input (NOT)	-	Flip Fl	•	
OR Ga	ites		L611	D-F/F	5
L212	2-input OR	2	L614	D-F/F with Set-Reset	7
L213	3-input OR	2	L617 L631	D-F/F with Set-Reset low D-F/F with C low	7
L214	4-input OR	3			5
	·		L637 L714	D-F/F with R low, S low, C low	7
NAND	Gates		L714 L717	Toggle-F/F with Set-Reset Toggle-F/F with Set-Reset low	7 7
L302	2-input NAND	1	L737	Toggle low F/F with Set-Reset low	7
L303	3-input NAND	2			
L304	4-input NAND	2	L922	4-bit D-F/F with Reset	23
L305	5-input NAND	3	L924	4-bit D-F/F	18
L306	6-input NAND	3	Shift F	Registers	
AND	Nation		L911	4-bit shift register with Reset	23
AND C	ates		L912	4-bit serial/parallel shift register	23
L312	2-input AND	2	L913	4-bit parallel in shift register with Reset low	27
L313	3-input AND	2	L914	4-bit shift register	18
L314	4-input AND	3		,	
AND-N	IOR Gates				
L421	2-wide 1-2-input AND-OR inverter	2			
L422	3-wide 1-1-2-input AND-OR inverter	2			
L423	2-wide 1-3-input AND-OR inverter	2			
L424	2-wide 2-2-input AND-OR inverter	2			
L425	3-wide 2-2-2-input AND-OR inverter	3			
L426	2-wide 3-3-input AND-OR inverter	3			
L429	4-wide 2-2-2-input AND-OR inverter	4			
L442	2-wide 4-4-input AND-OR inverter	4			
L462	3-wide 1-2-3-input AND-OR inverter	3			



Block	Description	Basic RAM	BIST	Cells	Block	Description	Basic RAM	BIST	Cells	
Memory Blocks					Memory Blocks					
High-S	peed Basic RAM Blocks - Hard Macr	os			High-S	peed Dual-Port RAM Blocks - Soft	Macros (C	ont.)		
KD49	Single-port RAM (32 word x 4 bit)		_	574	RK8F	Dual-port RAM (256 word x 8 bit)	KE8F	RU8F	8887	
KD8B	Single-port RAM (64 word x 8 bit)	_	_	1672	RK8H	Dual-port RAM (512 word x 8 bit)		RU8H		
KD8F	Single-port RAM (256 word x 8 bit)	_	_	5400	RKAB	Dual-port RAM (64 word x 10 bit)		RUAB		
KDAB	Single-port RAM (64 word x 10 bit)	_	_	1976	RKAD	Dual-port RAM (128 word x 10 bit)	KEAB	RUAD	5215	
KDAF	Single-port RAM (256 word x 10 bit)	_	_	6600	RKAF	Dual-port RAM (256 word x 10 bit)	KEAF	RUAF	10125	
KE49	Dual-port RAM (32 word x 4 bit)	_	_	820	RKAH	Dual-port RAM (512 word x 10 bit)	KEAF	RUAH	19969	
KE87	Dual-port RAM (16 word x 8 bit)	_		520	RKC9	Dual-port RAM (32 word x 16 bit)	KE49			
KE8B	Dual-port RAM (64 word x 8 bit)	_	_	2128	RKCB	Dual-port RAM (64 word x 16 bit)	KE8B	RUCB	4609	
KE8F	Dual-port RAM (256 word x 8 bit)	_	_	6000	RKCD	Dual-port RAM (128 word x 16 bit)	KE8B	RUCD	8927	
KEAB	Dual-port RAM (64 word x 10 bit)	_	_	2432	RKCF	Dual-port RAM (256 word x 16 bit)	KE8F	RUCF	17491	
KEAF	Dual-port RAM (256 word x 10 bit)	_	_	7200	RKEB	Dual-port RAM (64 word x 20 bit)	KEAB	RUEB	5249	
	,				RKED	Dual-port RAM (128 word x 20 bit)	KEAB	RUED	10183	
High-S	peed Single Port RAM Blocks - Soft	Macros			RKEF	Dual-port RAM (256 word x 20 bit)	KF49	RUH9	19968	
RJ49	Single-port RAM (32 word x 4 bit)	KD49	RU49	778	RKH9	Dual-port RAM (32 word x 32 bit)		RUHB		
RJ4B	Single-port RAM (64 word x 4 bit)	KD49		1381	RKHB	Dual-port RAM (64 word x 32 bit)		RUHD		
RJ4D	Single-port RAM (128 word x 4 bit)	KD49	RU4D	2556	RKHD	Dual-port RAM (128 word x 32 bit)		RUHD		
RJ4F	Single-port RAM (256 word x 4 bit)	KD49		4908	DIGGE	D 1	KEAD	DLUKD	40070	
RJ89		KD49	RU89	1384	RKKB	Dual-port RAM (64 word x 40 bit)		RUKB		
RJ8B	Single-port RAM (32 word x 8 bit) Single-port RAM (64 word x 8 bit)		RU8B	1924	RKKD	Dual-port RAM (128 word x 40 bit)	KEAD	RUKD	20116	
RJ8D	Single-port RAM (128 word x 8 bit)	KD8B		3632	High-D	ensity Single-Port RAM Blocks - S	oft Macro			
RJ8F	Single-port RAM (256 word x 8 bit)		RU8F	7009	ingii-b	ensity onigie-i of tham blocks	on macro.	•		
				10701	RB4D	Single-port RAM (128 word x 4 bit)	_	_	1170	
RJ8H	Single-port RAM (512 word x 8 bit)		RU8H		RB4F	Single-port RAM (256 word x 4 bit)		_	2133	
RJAB	Single-port RAM (64 word x 10 bit)		RUAB RUAD	2246 4262	RB4H	Single-port RAM (512 word x 4 bit)	_		4030	
RJAD RJAF	Single-port RAM (128 word x 10 bit) Single-port RAM (256 word x 10 bit)		RUAF	8247	RB4M	Single-port RAM (1K word x 4 bit)	_	_	7826	
ואסרו	Single-port HAM (230 Word X 10 bit)				RB4S	Single-port RAM (2K word x 4 bit)	_	_	15434	
RJAH	Single-port RAM (512 word x 10 bit)		RUAH		RB4U	Single-port RAM (4K word x 4 bit)	_	_	30532	
RJC9	Single-port RAM (32 word x 16 bit)	KD49		2602	RB8D	Single-port RAM (128 word x 8 bit)	_	_	2137	
RJCB	Single-port RAM (64 word x 16 bit)		RUCB		RB8F	Single-port RAM (256 word x 8bit)	_	_	3622	
RJCD	Single-port RAM (128 word x 16 bit)	KD8B	RUCD	7062	RB8H	Single-port RAM 512 word x 8 bit)	_		6999	
RJCF	Single-port RAM (256 word x 16 bit)	KD8B	RUCF	13789	RB8M	Single-port RAM (1K word x 8 bit)	_	_	11617	
RJEB	Single-port RAM (64 word x 20 bit)	KDAB	RUEB	4306	RB8S	Single-port RAM (2K word x 8 bit)	_		22958	
RJED	Single-port RAM (128 word x 20 bit)	KDAB	RUED	8318	RBAF	Single-port RAM (256 word x 10 bit)		_	4439	
RJEF	Single-port RAM (256 word x 20 bit)	KDAB	RUEF	16265	RBAH	Single-port RAM (512 word x 10 bit)	_		8619	
RJH9	Single-port RAM (32 word x 32 bit)	KD49	RUH9	5030	RBAM		_		14369	
RJHB			RUHB		RBAS		_		28450	
RJHD	Single-port RAM (128 word x 32 bit)		RUHD		RBCD		_		4077	
RJKB	Single-port RAM (64 word x 40 bit)	KDAB	RUKB	8423		, , , , , , , , , , , , , , , , , , , ,				
	0: to DAM (400 40 bit)	KOAD	DUKD	10407	RBCF	Single-port RAM (256 word x 16 bit)	_	_	7032	
RJKD	Single-port RAM (128 word x 40 bit)	KDAB	RUKD	16427	RBCH	Single-port RAM (512 word x 16 bit)	_	_	13764	
High-Speed Dual Port RAM Blocks - Soft Macros			RBCM		_	_	22989 7949			
nigii-a	peed buai Fort HAW Blocks - Soit W	iacios			RBHD	Single-port RAM (128 word x 32 bit)		_	7943	
RK49	Dual-port RAM (32 word x 4 bit)	KE49		1051	RBHF	Single-port RAM (256 word x 32 bit)	_	_	13844	
RK4B	Dual-port RAM (64 word x 4 bit)		RU4B	1910	RBHH	Single-port RAM (512 word x 32 bit)	_	_	27289	
RK4D	Dual-port RAM (128 word x 4 bit)	KE49		3690	RBKF	Single-port RAM (256 word x 40 bit)	_	_	17109	
RK4F	Dual-port RAM (256 word x 4 bit)	KE49	RU4F	6944	RBKH	Single-port RAM (512 word x 40 bit)	_	_	33769	
RK87	Dual-port RAM (16 word x 8 bit)	KE87	RU87							
RK89	Dual-port RAM (32 word x 8 bit)		RU89	1904						
RK8B	Dual-port RAM (64 word x 8 bit)		RU8B	2413						
	Dual-port RAM (128 word x 8 bit)		RU8D	4587						



Block	Description	Basic RAM	BIST	Cells	Block	Description	Basic RAM	BIST	Cells	
	Memory Blocks	(Cont.)			Memory Blocks (Cont.)					
РОМ Е	llocks				RAM T	est (BIST)				
114D 114F 114H 114M 114S 114U 118D 118F 118H 118S 118U 11CF 11CH 11CH 11CH 11CH 11CH 11CH 11CH	128 word x 4 bit ROM 256 word x 4 bit ROM 512 word x 4 bit ROM 1K word x 4 bit ROM 2K word x 4 bit ROM 2K word x 4 bit ROM 4K word x 4 bit ROM 128 word x 8 bit ROM 256 word x 8 bit ROM 512 word x 8 bit ROM K word x 8 bit ROM 4K word x 8 bit ROM 4K word x 8 bit ROM 4K word x 8 bit ROM 128 word x 8 bit ROM 1K word x 8 bit ROM 1K word x 16 bit ROM 1S6 word x 16 bit ROM 1K word x 16 bit ROM 1K word x 16 bit ROM 2K word x 32 bit ROM 512 word x 32 bit ROM 1K word x 32 bit ROM 1K word x 32 bit ROM 1K word x 32 bit ROM			720 1040 1512 2408 3960 6776 1040 1456 2352 3784 6600 11704 21584 1456 2352 3696 6512 11400 21280 3696 6512 11248 21128	RU49 RU4B RU4D RU4F RU87 RU89 RU8B RU8D RU8F RU8H RUAB RUAB RUAC RUCC RUCC RUCC RUCC RUCC RUCC RUCC	32 word x 4 bit 64 word x 4 bit 128 word x 4 bit 1256 word x 4 bit 16 word x 8 bit 32 word x 8 bit 64 word x 8 bit 128 word x 8 bit 512 word x 8 bit 512 word x 10 bit 128 word x 10 bit 128 word x 10 bit 128 word x 10 bit 129 word x 10 bit 110 word x 10 bit 1110 word x 10 bit 1110 word x 10 bit 1110 word x 10 bit 1111 word				



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Document No. 70020-5